

Search Notes

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Examiner

Oanh Duong

Applicant(s)/Patent under
Reexamination

NAKAYAMA ET AL.

Art Unit

2155

SEARCHED

Class	Subclass	Date	Examiner
709	203,217, 219,226, 229,248	8/6/2007	O.D

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search of USPAT, JPO, EPO, DERWENT, IBM_TDB, US- PBPUB	8/6/2007	O.D